



Mechanical Data	Notes
Dice size	AX=AY:210um, BX=BY:85um
Wafer size	4"
Chip Thickness	138um±12um
Scribe line width	40um
Top metal	Al for wire bonding, d=2.2um±0.2um
Back side metal	Ti-Ni-Ag for soldering

Parameter	Symbol	Conditions	Value	Unit
Reverse stand-off voltage	VRWM		5.0	V
Peak pulse power	Ppp	Tp=8/20us	35	W
Peak pulse current	IPP	Tp=8/20us	2.0	A
Electrostatic discharge	VESD	IEC61000-4-2 Level 4	± 15(AIR) ± 8(Contact)	KV
Max.junction temp.	Tj		+150	°C

Characteristics TA=25°C

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Breakdown voltage	VBR	IT=1mA	5.6		9.4	V
Reverse leakage current	IR	VR=5V			0.09	uA
Clamping Voltage	VC	IPP=1A IPP=2A			10.0 13.0	V
Diode capacitance pin1 to 2	Cj	VR=0V f=1MHZ		3.0	3.5	pf

Notes:

- (1)sampling testing:no bad dice inking/guaranteed good die >93%
- (2)Testing follow customer
- (3) $T_j = T_a + R_{th(j-a)} * (p_f + p_r)$ , where  $R_{th(j-a)}$ -thermal resistance,  $P_f$ -forward power dissipation,  $P_r$ -revers power dissipation
- (4)\*\*For device testing